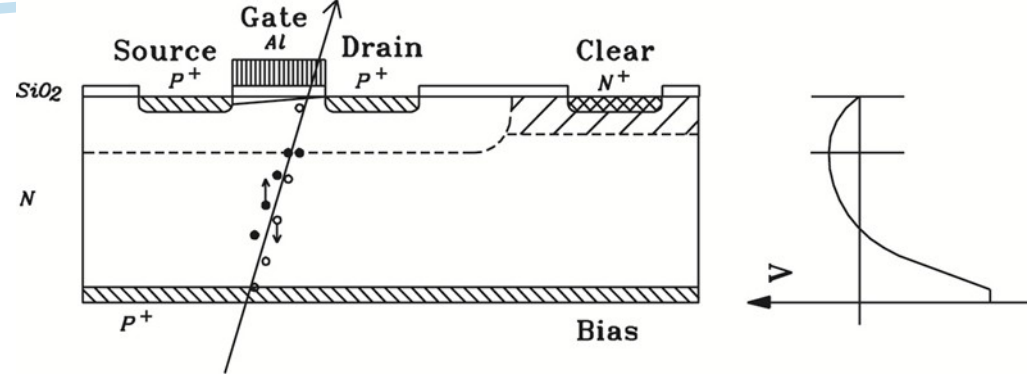


# The DEPFET Detector-Amplifier Structure for Spectroscopic Imaging in Astronomy and for Experiments at Free Electron Lasers

G. Lutz , S. Aschauer, P. Majewski, P. Holl and L. Strüder

# Introduction



DEPFET by J.Kemmer and G.Lutz invented and patented 1985, published 1987.

Initiated by E.Gatti and P. Rehaks Semiconductor Drift Detector (1983).

Basic concept Field Effect Transistor on top of a fully depleted bulk

Potential minimum for electrons below the transistor channel.

Signal electrons assemble in this „Internal Gate“ and steer the current.

Function principle verified soon after invention.

Meanwhile many applications and modifications of DEPFETs have been developed:

DEPFET Pixel detectors, Macropixel detectors, gateable DEPFETs, RNDR DEPFETs with subelectron precisions, Intermediate charge storage DEPFETs, DEPFETs with nonlinear characteristics and high dynamic range (DSSC)

# Content

DEPFET principle and properties

DEPFET pixel sensors

Macro Pixel Sensors

BepiColombo Mercury Mission

DEPFETs for Experiments at Free Electron Lasers

with nonlinear characteristics and high dynamic range

RNDR DEPFET sensors (subelectron noise)

Gateable DEPFETs

[Gateable RNDR DEPFET sensors]

Deadtime-Less DEPFET sensors

Summary and Outlook

# DEPFET principle

## DEPFET (DEpleted Field Effect Transistor)

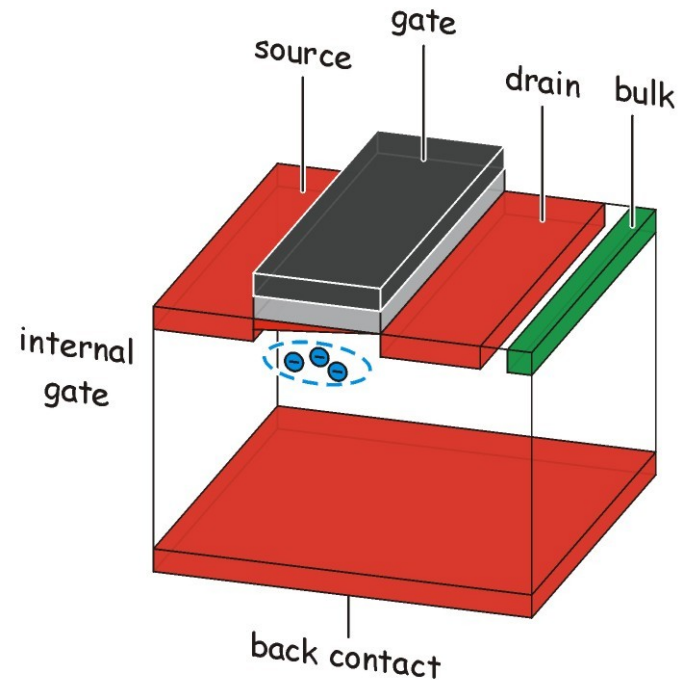
All charge generated in fully  
(sidewise) depleted bulk  
**drifts** into potential minimum  
underneath the transistor channel  
(internal gate)

steers the transistor current

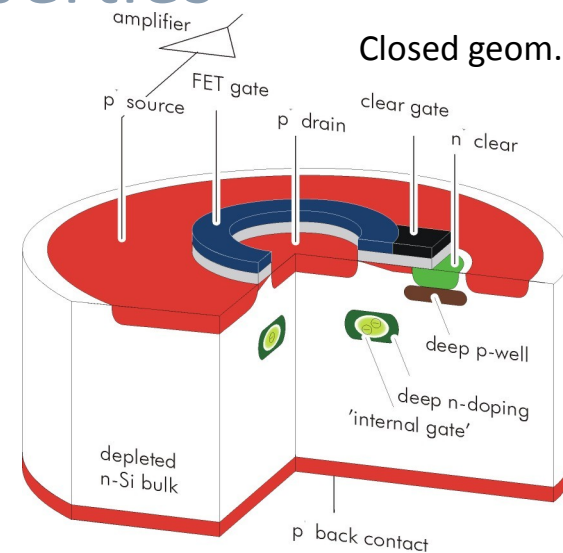
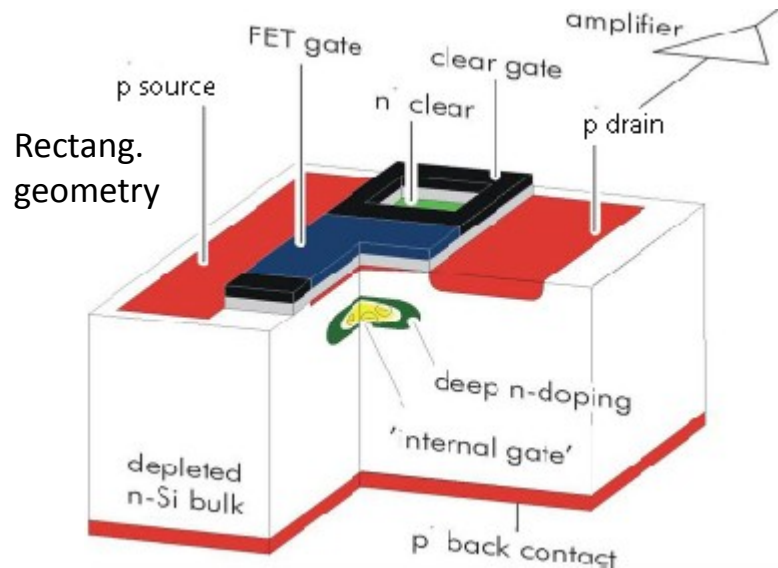
Clearing by positive pulse on clear  
electrode

Charge measured by difference of  
current with/without charge in the  
internal gate

**Combined function of sensor,  
amplifier and memory cell**



# DEPFET properties



Charge collection by drift mechanism over **full wafer thickness**

low capacitance ► **low noise**

Signal charge remains undisturbed by readout ► **repeated readout possible**

Complete clearing of signal charge ► **no reset noise**

Full sensitivity over whole bulk ► **large signal for m.i.p.; X-ray sens.**

Thin radiation entrance window on backside ► **X-ray sensitivity**

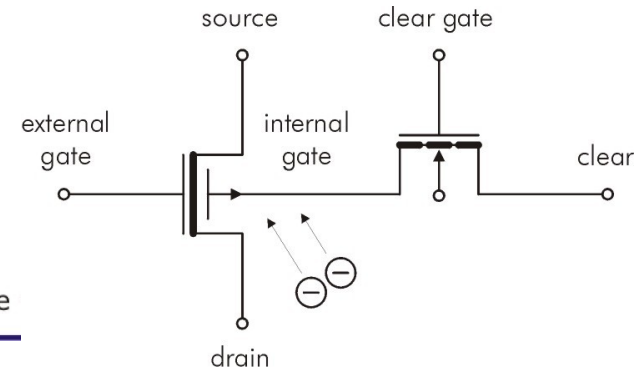
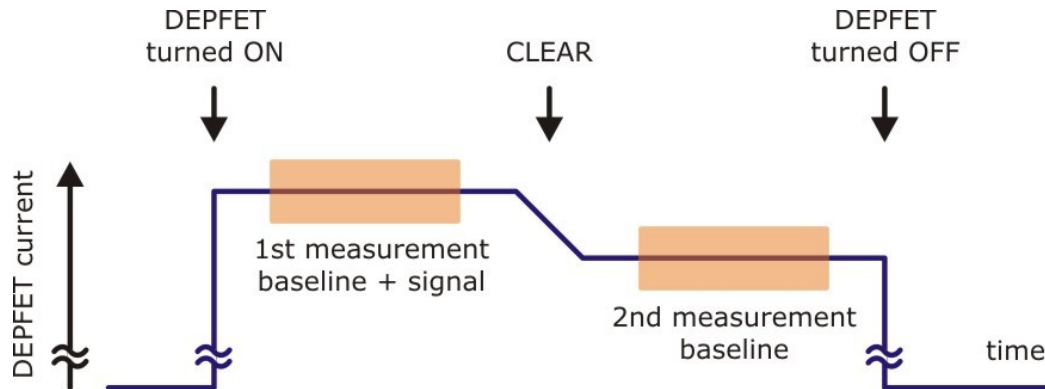
Charge collection also in turned off mode ► **low power consumption**

Measurement at place of generation ► **no charge transfer (loss) ►**

**Operation over very large temperature range ► no cooling needed**

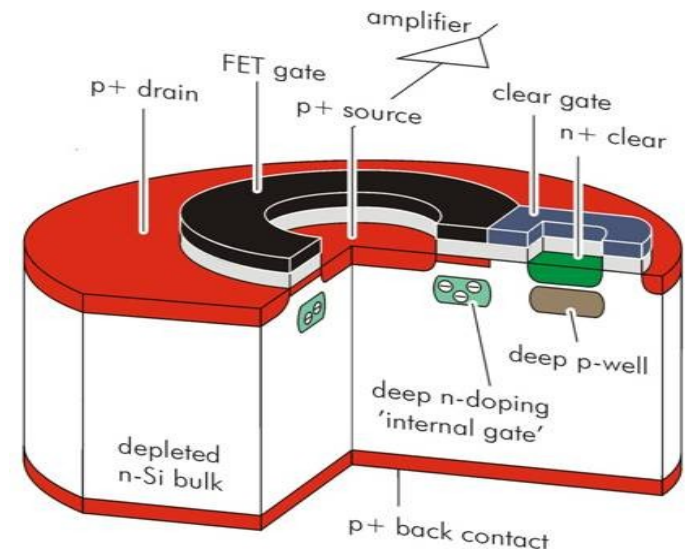
**Combined function of sensor, amplifier and memory cell**

# DEPFET Readout



## ■ **Measurement of signal**

- ▷ **Measure signal levels**
  - ▷ **source potential / drain current**
- ▷ **Measure both before and after clear**
- ▷ **Calculate the difference**
  - ▷ **correlated double sampling (CDS)**



# DEPFETs as pixel detector

Fill large area with DEPFETs

Connect electrodes (source, gate, drain, clear) so as to allow individual DEPFETs to be powered (read out)

Individual transistors  
or rows of transistors  
can be selected for readout

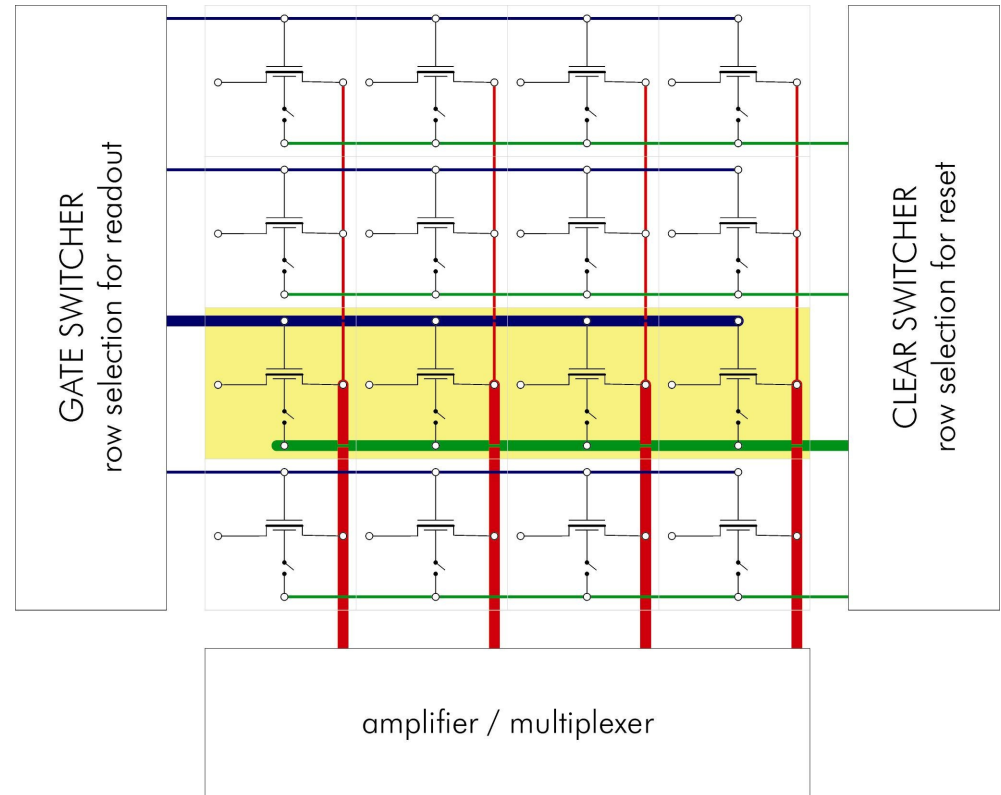
All other transistors  
are turned off

Those are still able  
to collect signal charge

Very low power  
consumption

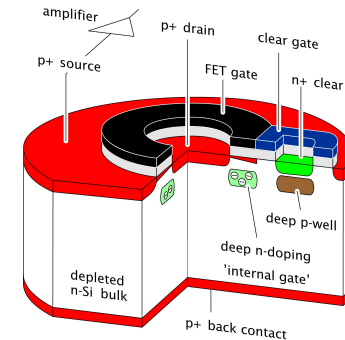
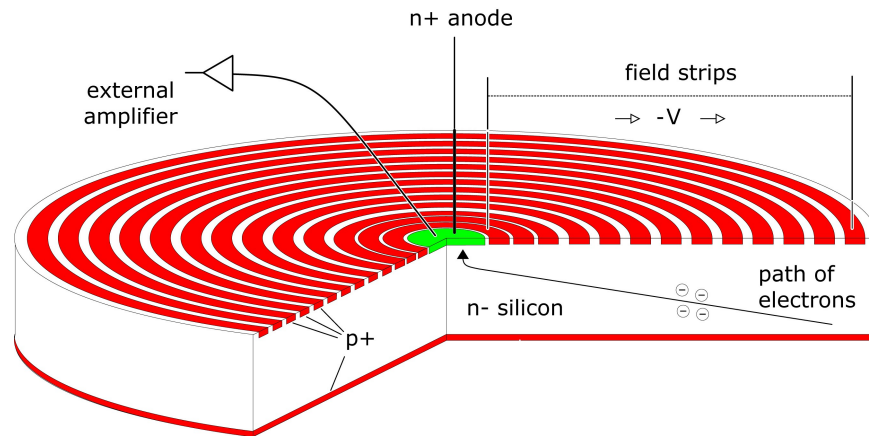
## Charge measurement:

difference of drain current  
with full and empty internal gate  
(before and after clear or  
before and after signal)



# Macro-pixel detector

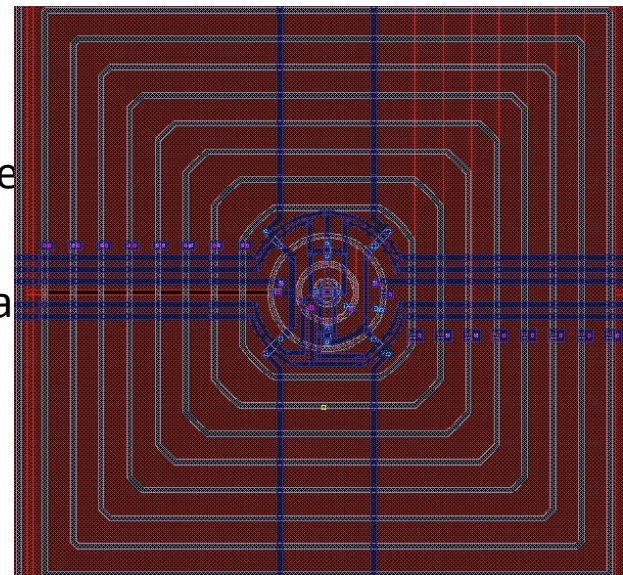
## Combination of SDD (Silicon Drift Diode) with DEPFET



Each cell consist of drift diode  
with DEPFET as readout e

Cell size can be chosen (adapted  
to the application) over a  
very wide range

Application: BepiColombo Mercury Mission





# BepiColombo Mercury Mission

Physics goal: Investigation of Mercury (least well explored planet in our solar system due to harsh environment: high temperature, radiation, difficulty in deceleration)

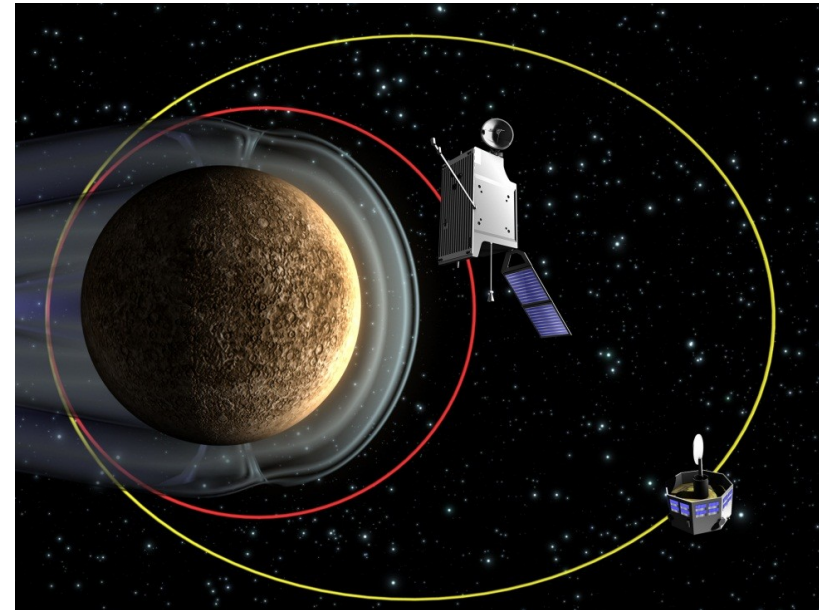
Magnetic field, Geological composition and history of Mercury

Two satellites on same spacecraft:

MMO (Mercury Magnetospheric Orbiter) and  
MPO (Mercury Planetary Orbiter) on common  
Transfer Module to be separated after  
deceleration with the help of other  
planets.

Launch: February 2017

Arrival: January 2024



# DEPFET Macro-pixel detector in MIXS (Mercury image X-ray Spectrometer) on MPO

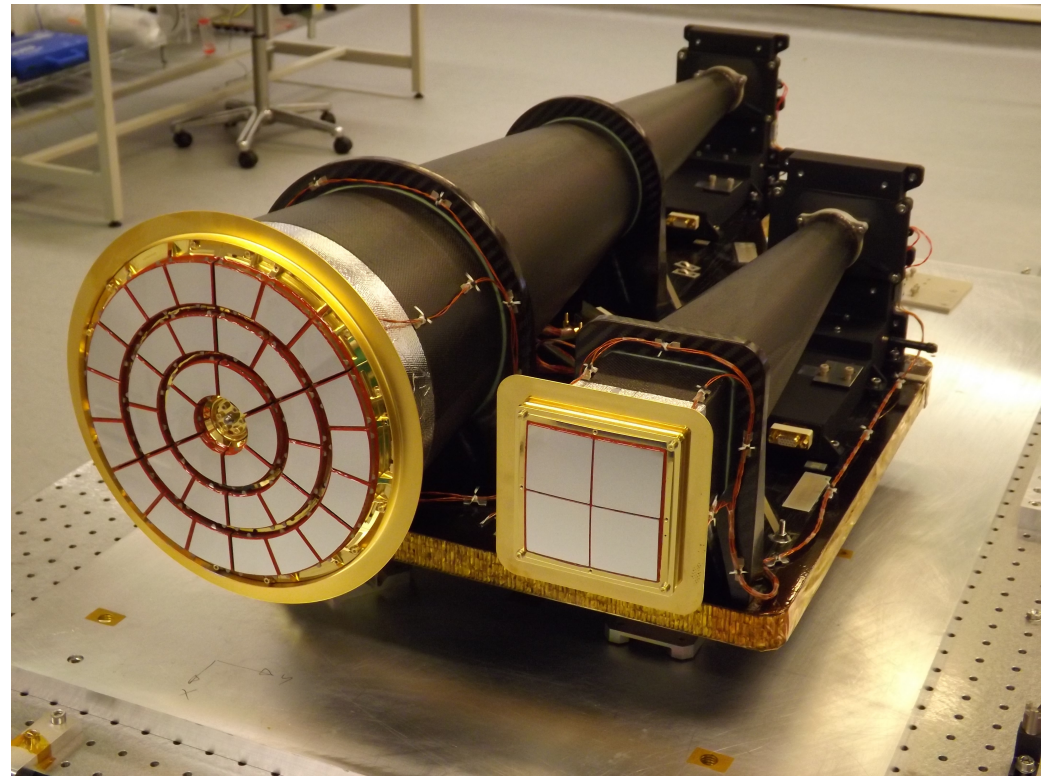
Purpose: investigate experimental composition of Mercury surface from X-ray fluorescence induced by the solar wind.

Two Instruments:

1) MIXS-T Mirror Imaging

2) MIXS-C Collimating

Identical focal plane sensor



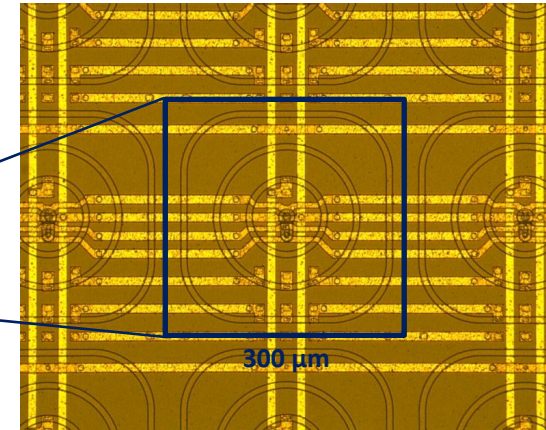
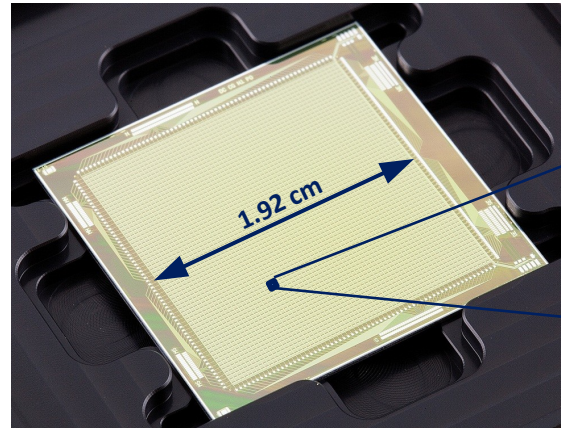
# Macro-pixel detector for MIXS

*MIXS will be the first space instrument flying DEPFET detectors*

*Fully assembled and tested, waiting for launch*

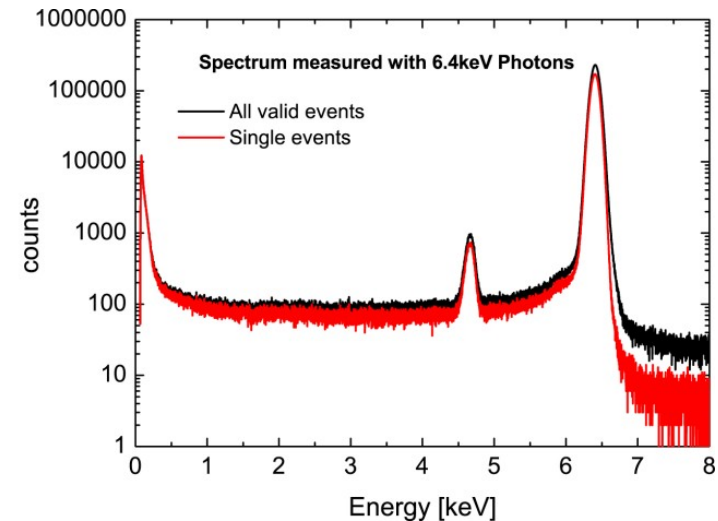
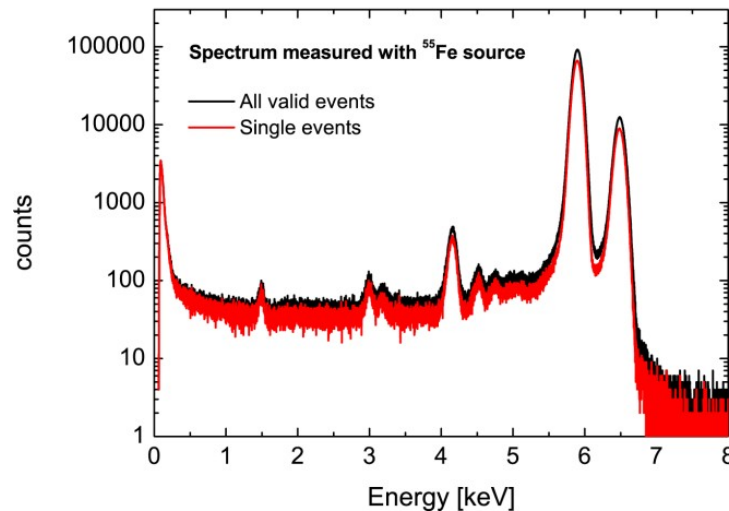
Main Detector requirements:

- active area:  $1.92 \times 1.92 \text{ cm}^2$
- pixel size:  $300 \times 300 \text{ }\mu\text{m}^2$ 
  - 64 x 64 pixels
- energy range:  $0.5\text{keV} \leq E \leq 7\text{keV}$
- energy resolution  $\leq 200\text{eV}$  @  $1\text{keV}$ 
  - at mission end
- radiation hardness



# MIXS Focal Plane Detector Properties

MIXS focal plane detectors have been tested. All requirements have been reached or surpassed including spectroscopic properties and radiation hardness



X-ray spectra with Fe55 source and with monochromatic 6.5 keV photons  
165  $\mu\text{s}/\text{frame}$ , Energy resolution at 5.9 keV is  $\Delta E = 129.5 \text{ eV}$  (FWHM)

# DEPFETs for Experiments at Free Electron Lasers

## DEPFET Sensor with Signal Compression (DSSC) Pixel Detector

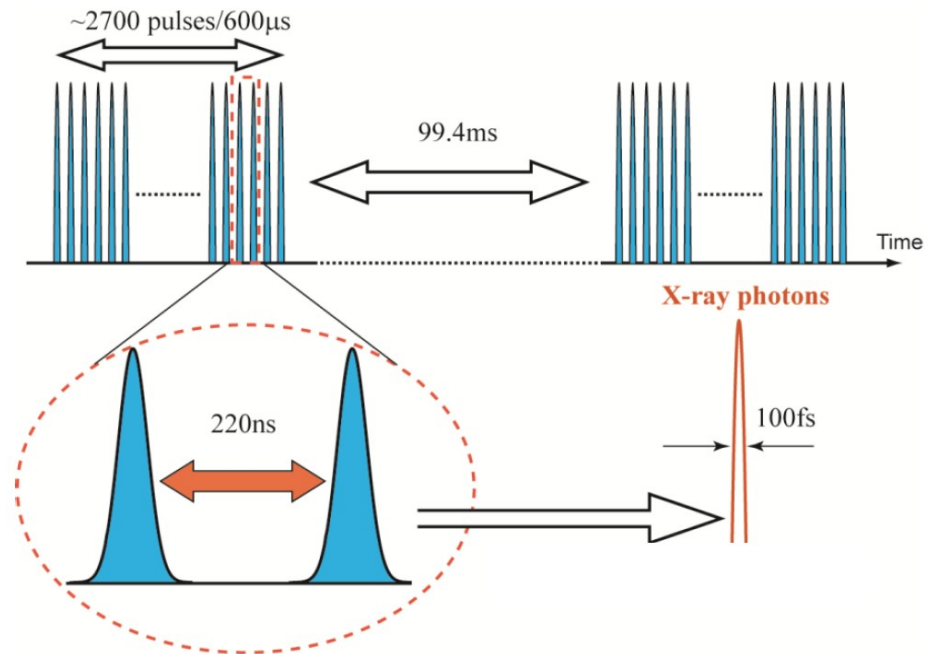
Developed for experiments at the European X-ray Free Electron Laser requiring simultaneously detection of single X-ray Photon in one pixel and up to 10000 photons in other close by pixels.

In addition extremely fast readout was required due to the bunch structure of the accelerator.

Concept:

DEPFET with nonlinear characteristics

Parallel readout of every pixel





# DEPFET with Non-Linear Characteristic

## Standard DEPFET principle

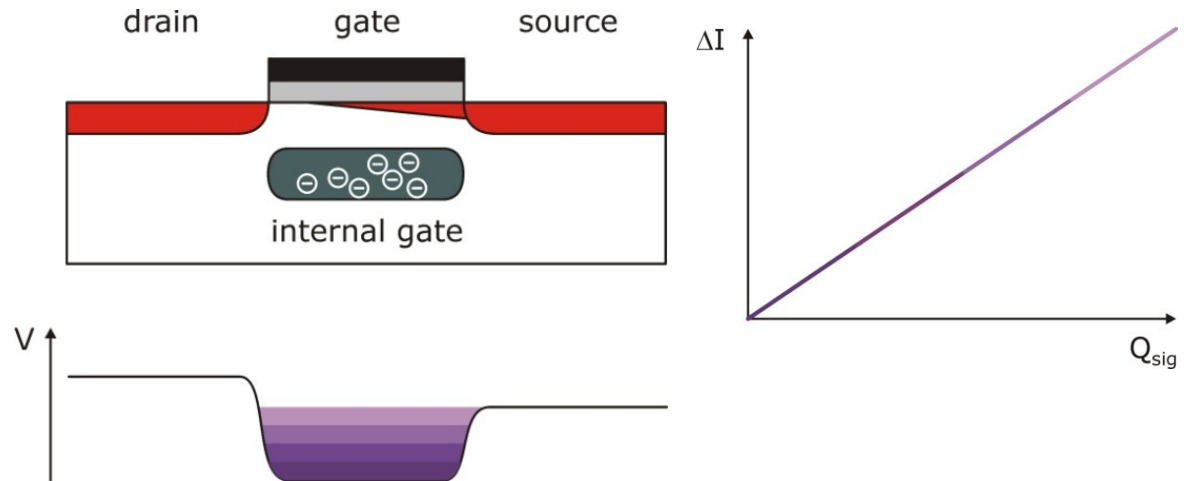
- p-FET on depleted n-bulk
  - ↳ All signal charge collected in potential minimum below FET channel

"internal gate"

all signal charges cause an equal effect on the FET current

**linear  $\Delta I/Q_{sig}$  characteristics**

- reset via ClearFET
- low capacitance & noise

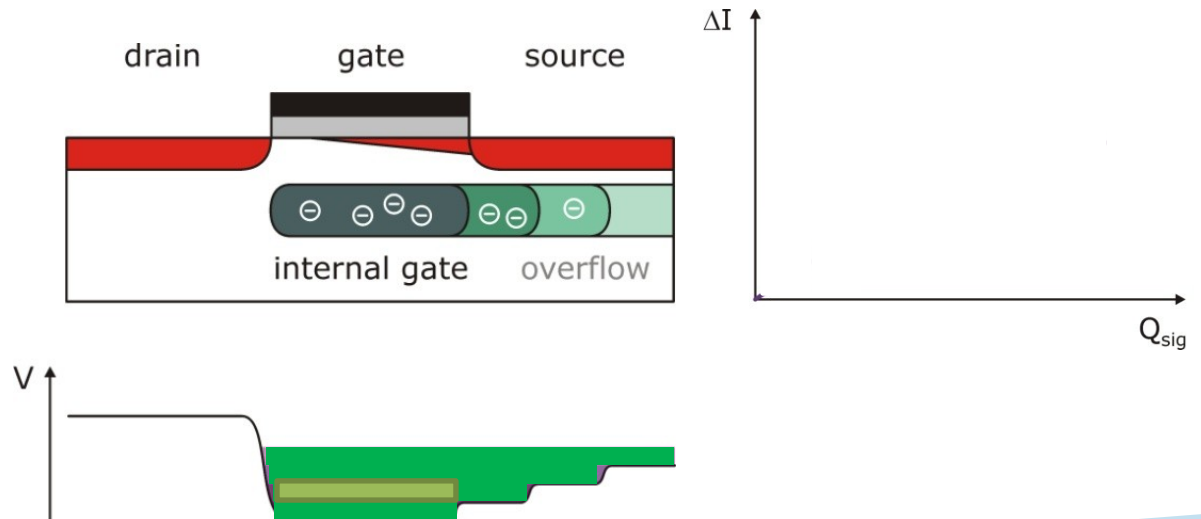


## DSSC adaptation

signal charges at high levels also stored under source  
less/no effect on FET current

**non-linear  $\Delta I/Q_{sig}$  characteristics**

gain curve engineering by dose & geometry of implantations



# DSSC – Design Parameters

| Parameter                        |   |
|----------------------------------|---|
| Energy range                     | optimized for 0.5 ... 6 keV                       |
| Number of pixels                 | 1024 x 1024                                       |
| Sensor Pixel Shape               | Hexagonal   |
| Sensor Pixel pitch               | ~ 204 x 236 $\mu\text{m}^2$                       |
| Dynamic range /<br>pixel / pulse | ~5000 ph @ 0.5 keV<br>> 10000 ph @ $E \geq 1$ keV |
| Resolution                       | Single photon detection<br>also @ 0.5 keV         |
| Frame rate                       | 0.9-4.5 MHz                                       |
| Stored frames per<br>Macro bunch | $\geq 640$  |
| Operating<br>temperature         | -20°C optimum, RT<br>possible                     |

1 Mpixel camera with:

- Single photon sensitivity event at 0.5 keV
- 
- high-dynamic range (>10000 ph/pixel)
- 
- Frame rate up to 4.5 MHz (1 image every 220 ns)
- 

All the properties have to be achieved simultaneously

DSSC will be the first instrument to fulfill this requirement

# DSSC: focal plane architecture



- 1024 x 1024 pixel  
Every DEPFET pixel provides detection and amplification with **signal compression at the sensor level** (nonlinear DEPFET)
- focal plane composed of 32 monolithic sensor chips (128 x 256 pixel)
- Each sensor is bump bonded to 8 readout ASIC chips: fully parallel readout at 0.9-4.5 MHz

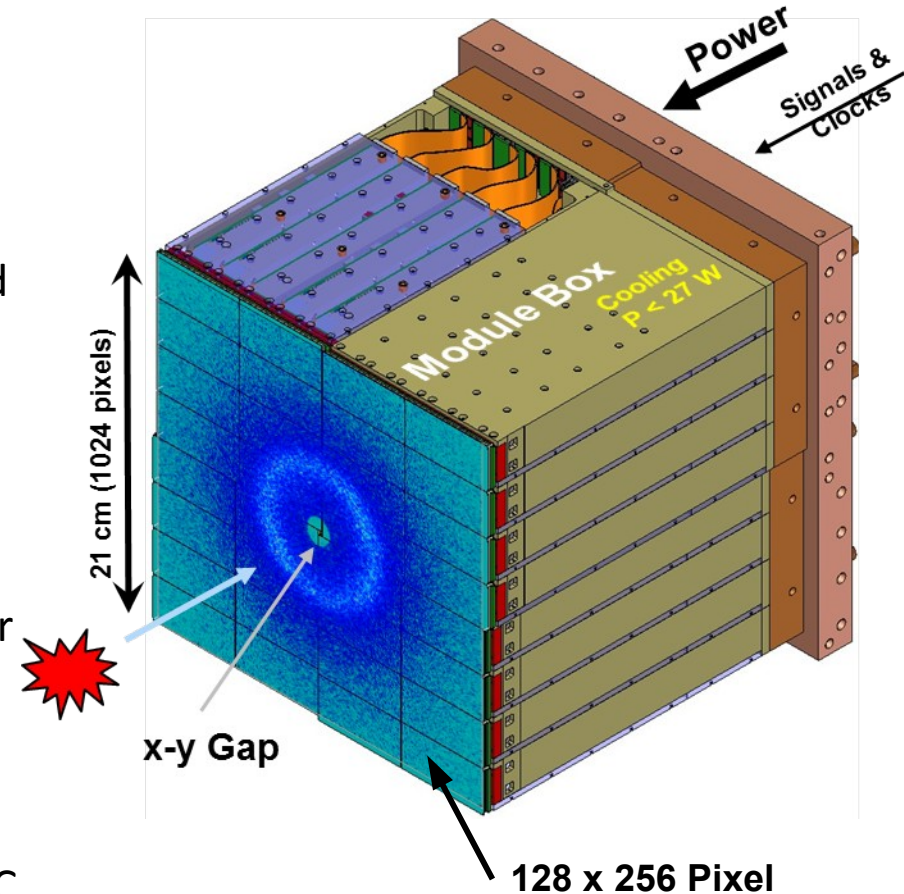
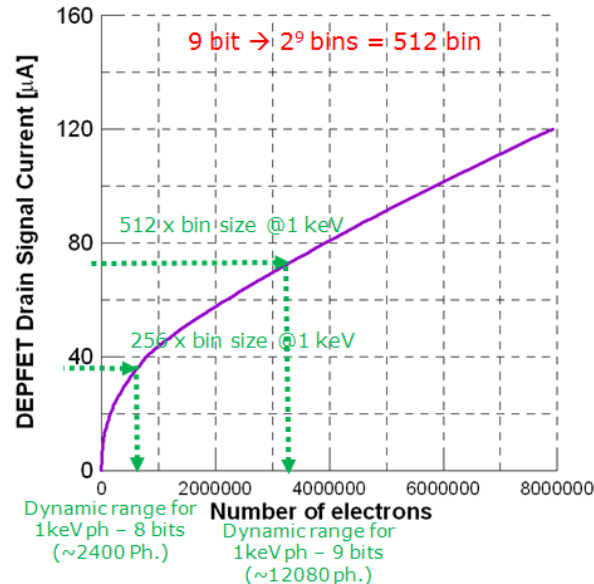
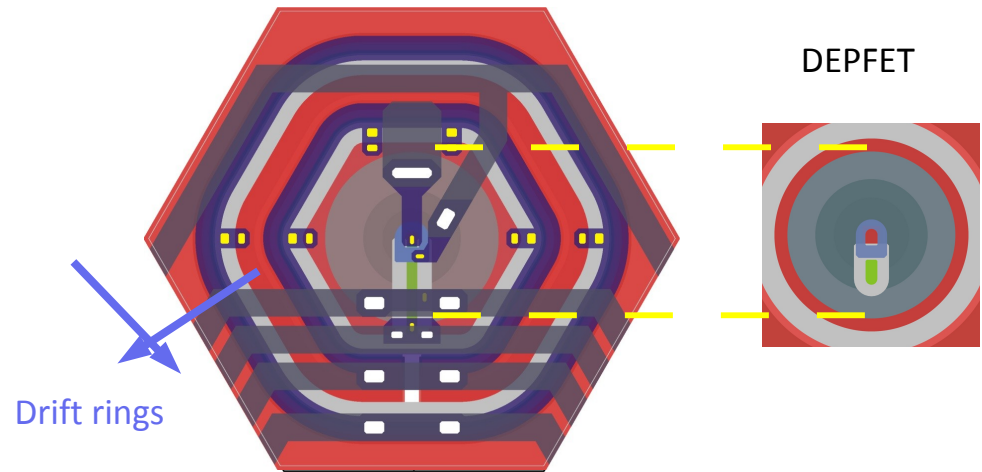
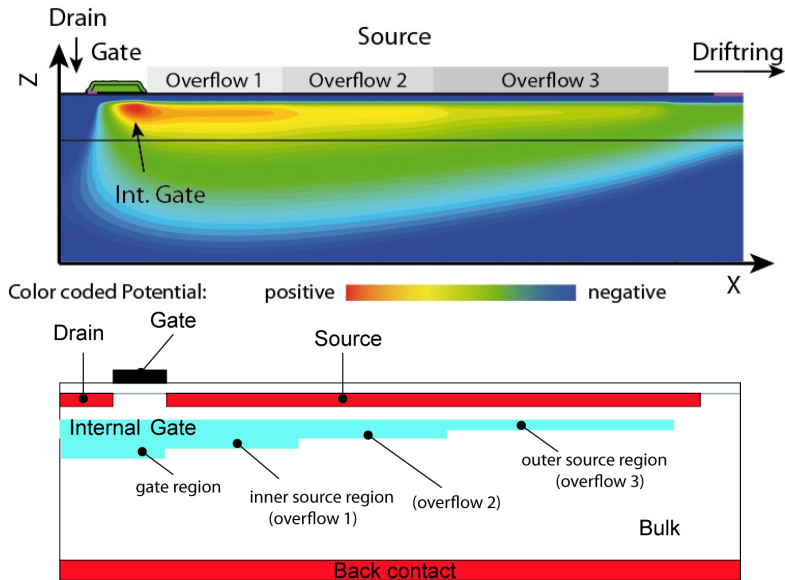


Image: K. Hansen, DESY



# DSSC DEPFET – Simulation and Layout

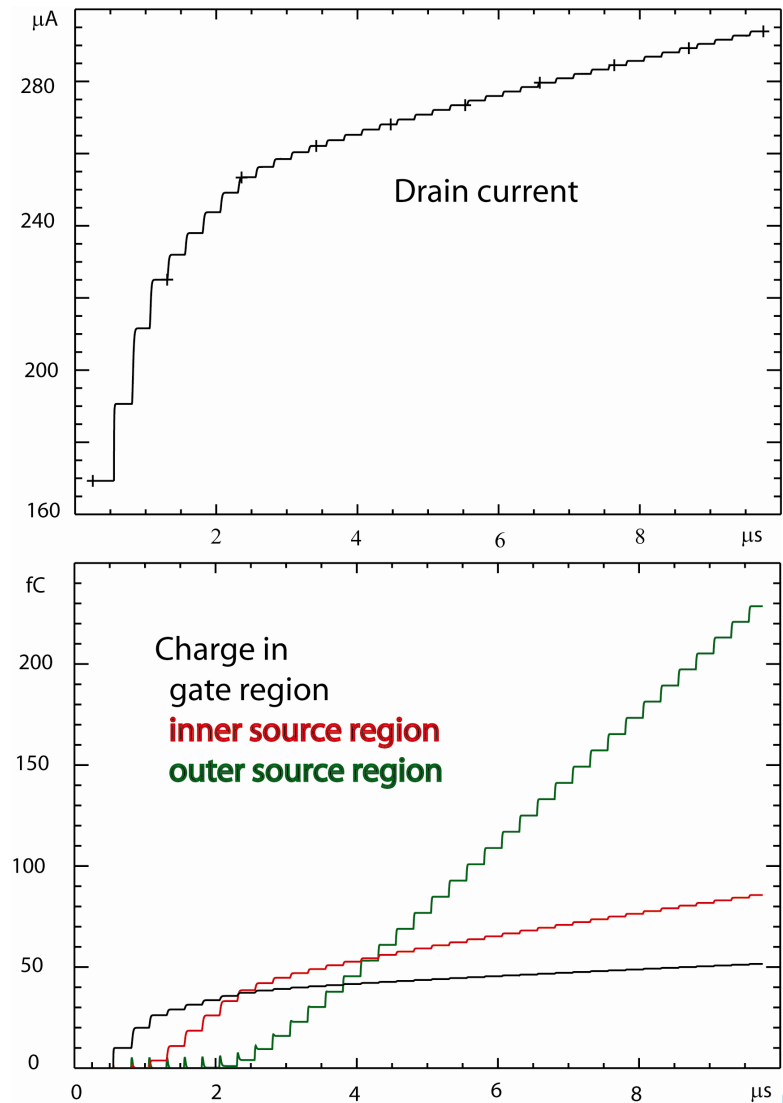


- hexagonal shape
  - side length 136 μm ( $A=48144 \mu\text{m}^2$ )
- technology
  - 2 polySi layers
  - 2 metal layers
  - 12 implantations

# Non-linear DEPFET: Simulation

Charge distribution in internal gate and  
Resulting drain current

37 consecutive steps of  $1\text{e-}14$  C charge  
deposition were simulated



# Experimental tests on DSSC prototypes

## spectroscopy

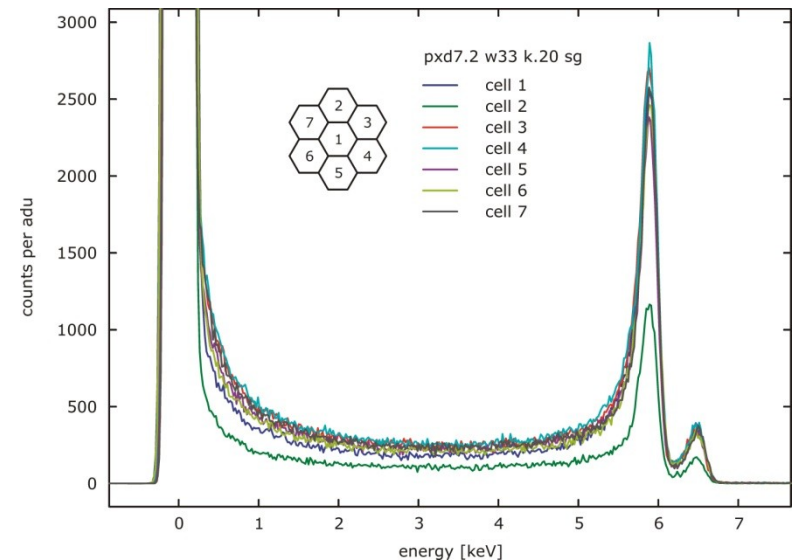
- Fe55 source

linear region of the gain curve

noise peak  $\sim 10$  el. ENC

Mn-K<sub>α</sub> line  $\sim 150$  eV FWHM @

5.9 keV



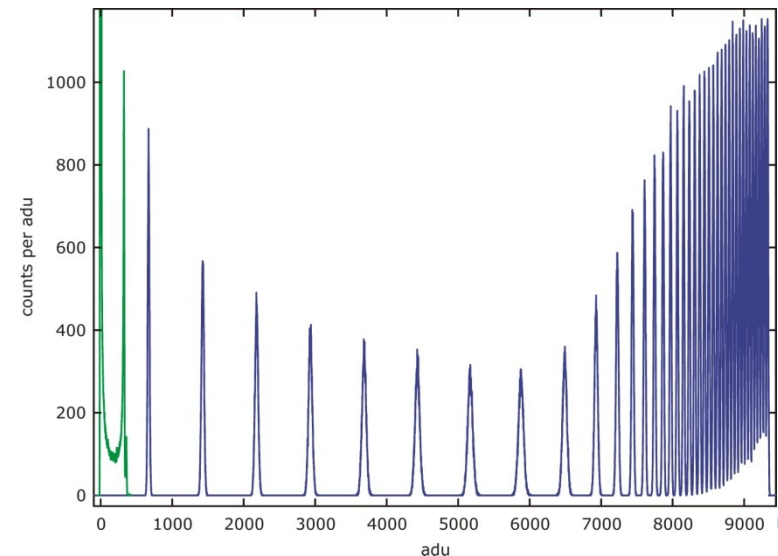
## Response to a pulsed laser

increasing number of identical pulses

peaks are equidistant in terms of signal charge

signal compression @ large charge amount

"energy" calibration using Fe55 spectrum



# Status of DSSC DEPFET Sensors

Prototypes produced in Scientific Laboratory proved correct functioning fulfilling all requirements.

The yield was lower than expected.

At present the process and design is adapted to produce the sensors in an industrial type production line. This allows for additional improvements due to smaller feature sizes as well as faster turn-around time

# DEPFETs so far described

## Basic DEPFET

Signal charge stored in potential minimum below the transistor channel

Combined detector and amplifier properties

Low readout noise and absence of reset noise: excellent spectroscopic performance

Fully depleted, backside illumination: 100% fill factor, high quantum efficiency

Nondestructive readout of signal charge

Room temperature operation possible

Arranged into a pixel matrix a DEPFET detector has the advantage of

- \* Low power consumption, as transistors are turned off during charge collection
- \* Charge readout at place of generation, no charge shifting needed
- \* Readout on demand and window-mode capability
- \* High speed operation possible
- \* Significantly improved radiation hardness compared to CCDs

## DEPFET combined with Silicon Drift Detector (Macropixel detector)

Pixel cell size can be varied from tens of  $\mu\text{m}$  to centimeters

The detector can be easily tailored to the telescope's point spread function

## DSSC DEPFET ( DEPFET Sensor with Signal Compression)

Intrinsic non-linear amplification, tunable by doping and operation voltages

Combines high dynamic range with excellent resolution for small signals

# DEPFETs not yet described

## **Repetitive Non-Destructive Readout (RNDR) DEPFET** detectors

Repetitive readout of the signal allows sub-electron measurement precision  
useful for low energy x-ray spectroscopy and photon counting in the optical

## **Gateable DEPFET** detectors

Intrinsic electronic shutter: collection of signal charge only in selected time intervals  
Suppression of “misfits” (due to arrival of signals during readout phase): improved  
signal-to-noise ratio for high speed applications

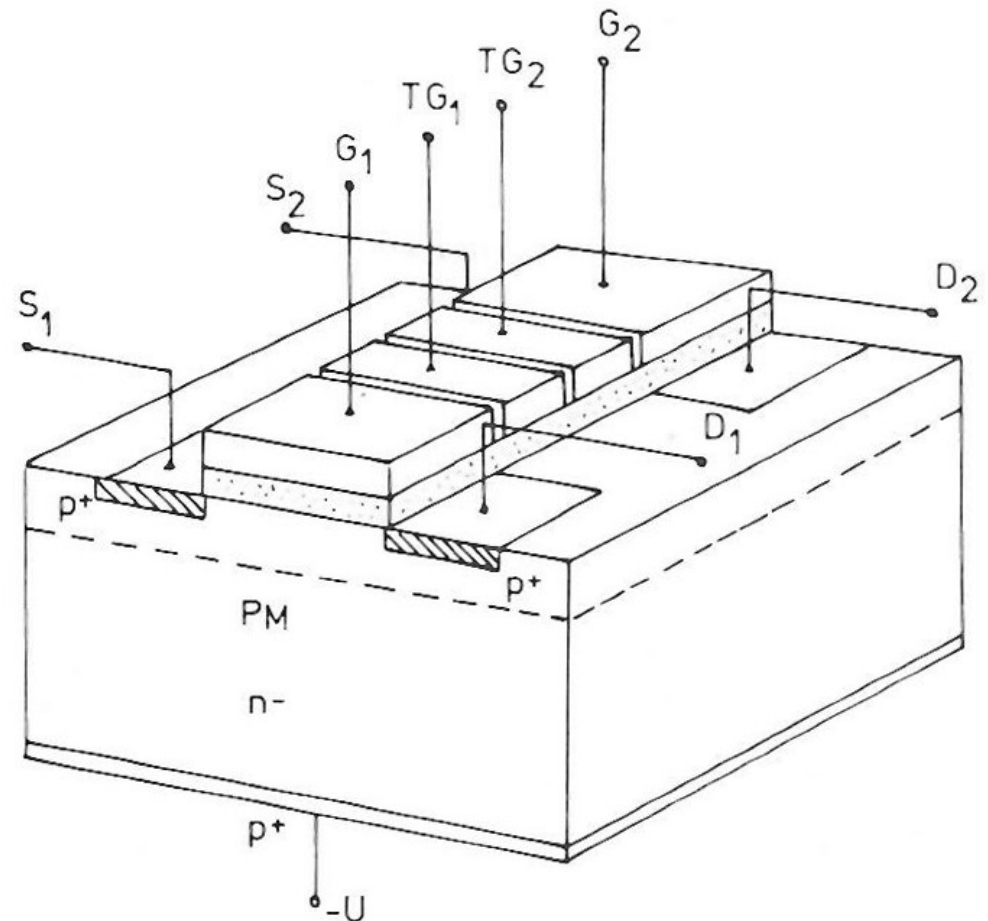
## **Gateable DEPFETs with intermediate charge storage**

Allows nearly dead-time-free operation and/or gateability  
Optimized for spectroscopy at high frame rates

# RNDR DEPFET Detector

The proposal of using the non-destructable reading in DEPFETs for reducing the noise was already contained in the original DEPFET publication.

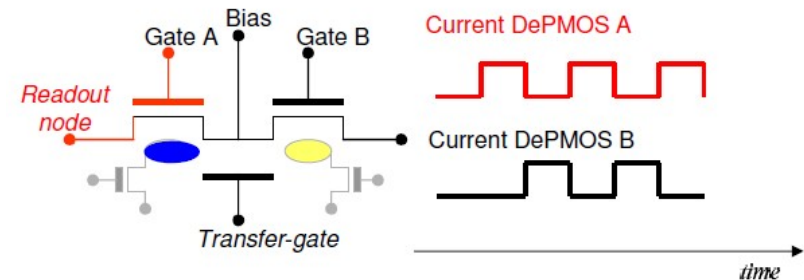
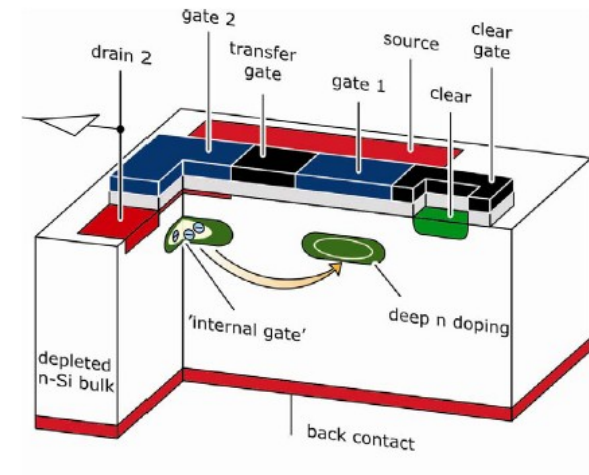
Two DEPFETs placed close to each other were connected with a CCD like structure allowing the shifting of signal charge from one IG to the other and reverse. Such it was possible to read the same charge multiple times and reduce the noise by the square root of the number of readings.



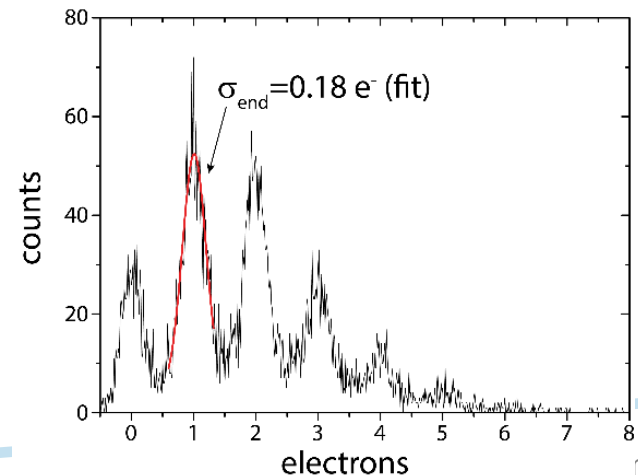
# RNDR DEPFET Detector

Developed in the framework of a PhD thesis(Stefan Wölfel)

Aim: demonstrate sub-electron charge measurement precision, suppression of 1/f noise



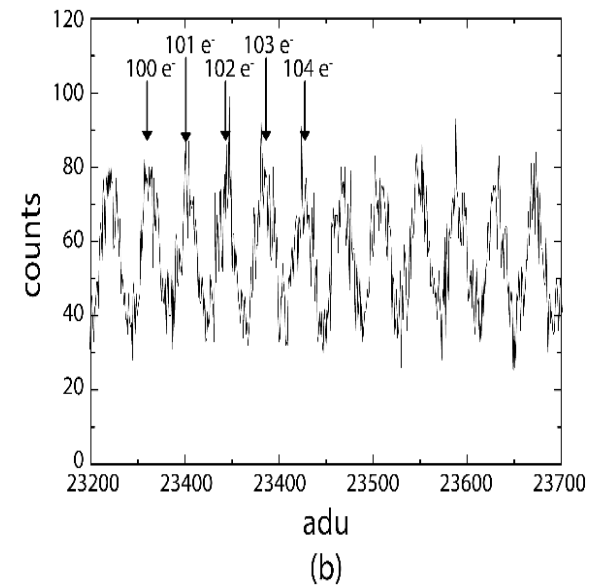
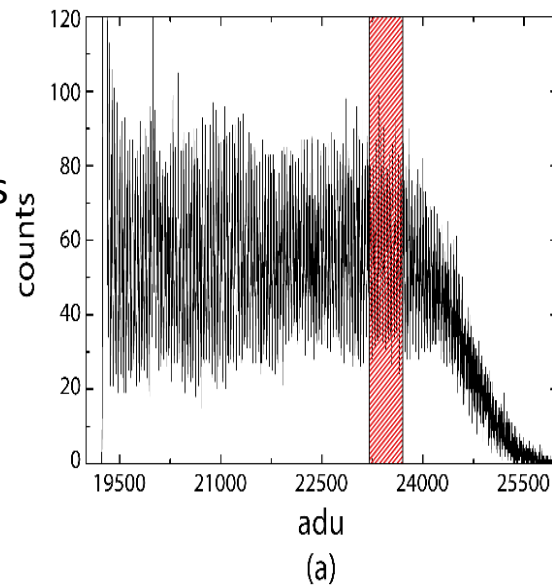
Exposure with faint light source  
(1 photon per exposure on average)  
Resolution 0,18 el. r.m.s.





# RNDR DEPFET Detector

Extending exposure time  
Continuously all channels  
are populated



Number of electrons can be measured with same precision up to very high numbers.

Applications in low energy X-ray spectroscopy,  
Optical photon counting

# Gateable DEPFET Sensors

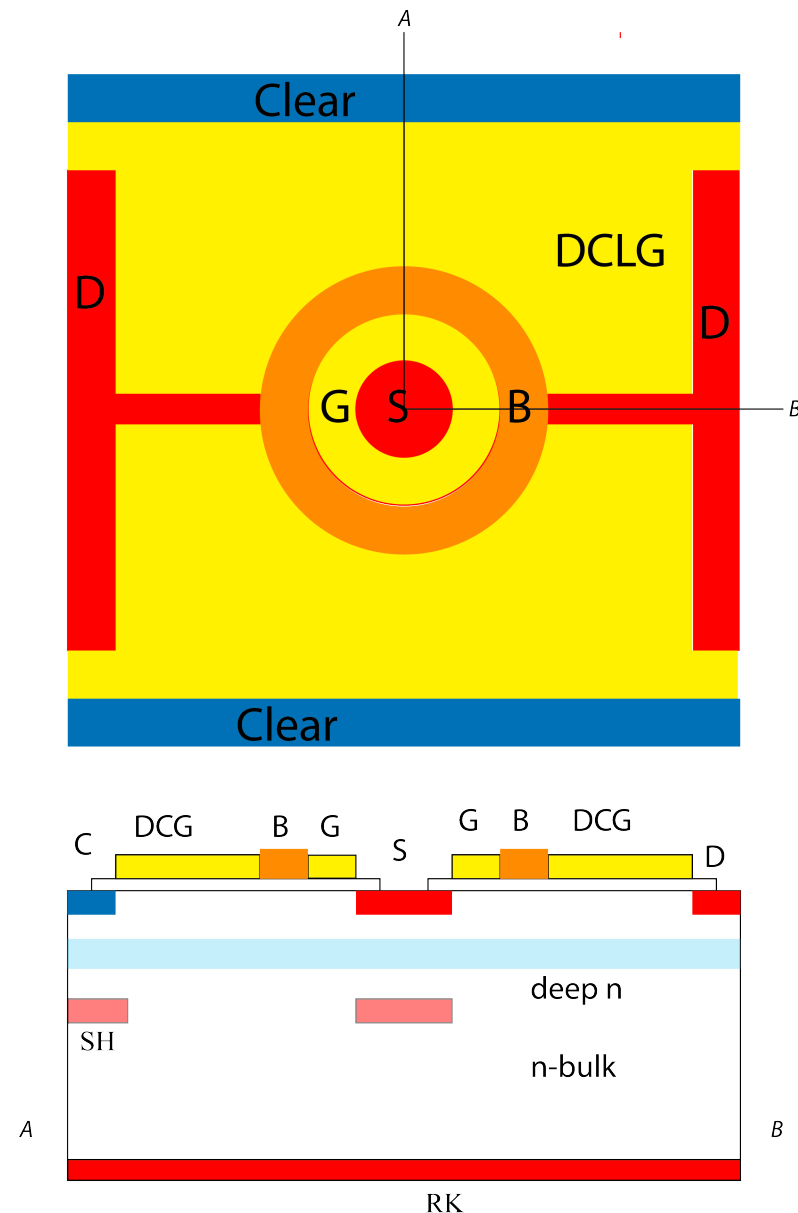
DEPFETs described so far were continuously sensitive. Charge was collected in the Internal Gate, even during readout.

To restrict charge collection to desired time interval an externally controllable shutter can be integrated into the DEPFET.

Source (S) surrounded by Gate (G) and Barrier Gate (B).

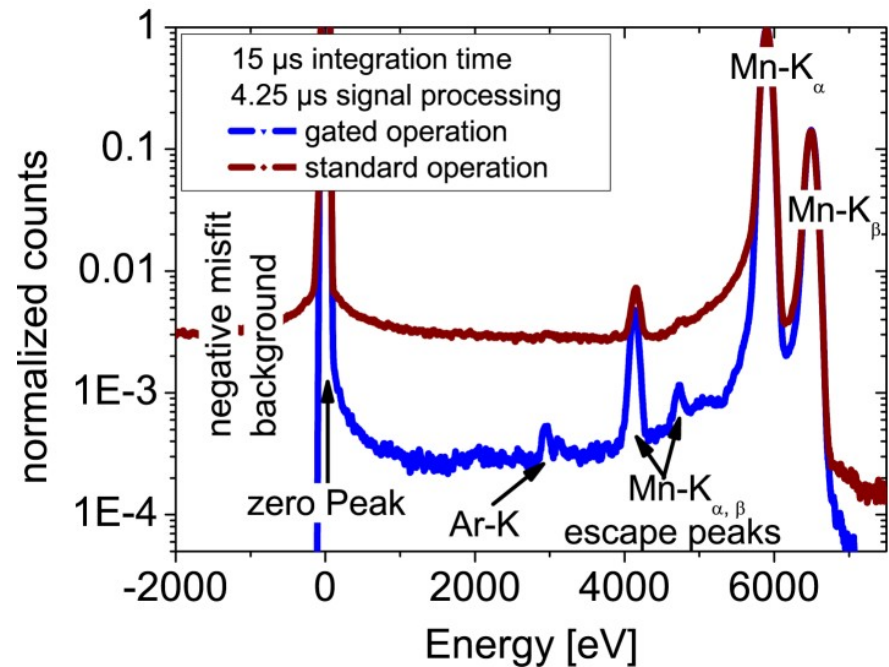
Outer region covered by Drain-Clear-Gate (DCG) creating underneath either (for negative voltage) an inversion layer (connected to the drain) or for positive voltage an accumulation-layer connected to Clear.

Barrier gate B controls flow of signal charge out of Internal gate.



# Gateable DEPFET Sensors

Gateable pixel sensors can be used for observation of periodically varying objects and for suppressing events occurring during the readout phase of the device  
(misfit events)



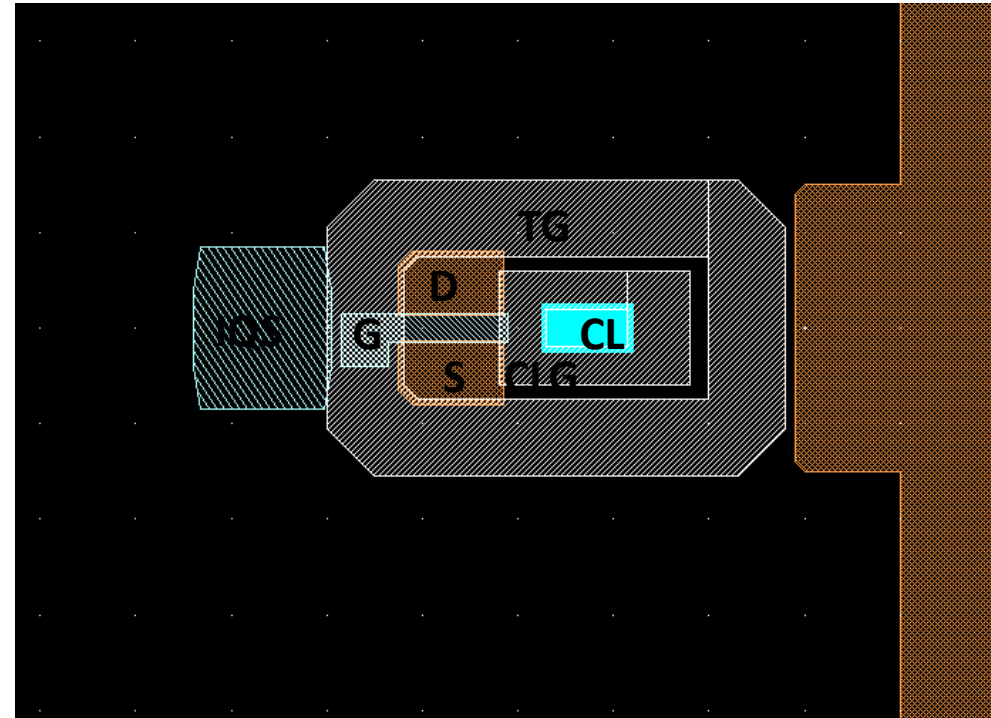
# IQS (Intermediate Charge Store) DEPFETs

## Gateable DEPFETs with intermediate charge storage

For applications in X-ray astronomy a fast gateable pixel detector with continuous deadtime-less sensitivity was desired.

Concept: collect data in intermediate storage regions outside of the DEPFETs while data from previous event are read out.

Transfer complete event rapidly into DEPFET regions of the pixels.



# Summary and Outlook

DEPFET is a very old concept (1985) that only recently has found its way into large projects (MIXS, DSSC, BELLE II)

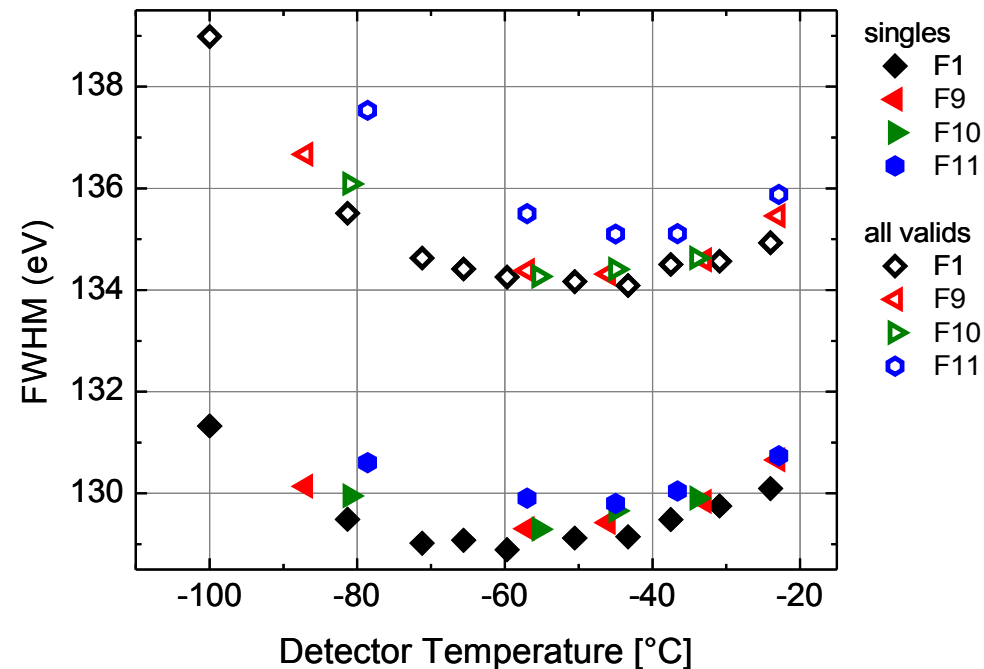
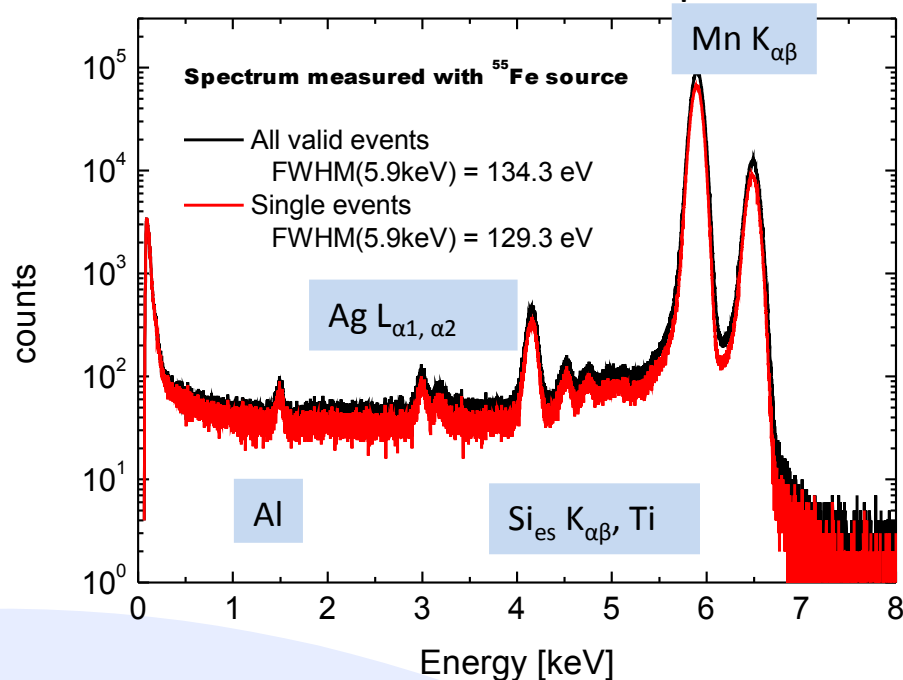
It combines detector and amplifier and signal storage properties and can be adapted to many requirements.

# Detector performance

## 2. spectroscopic performance measurements: $^{55}\text{Fe}$ source 5.9 keV ( $\text{Mn } K_{\alpha\beta}$ )

readout speed: 165  $\mu\text{s}/\text{frame}$

measurements over a wide temperature range



# Detector performance

## 3. calibration measurements @ BESSY-II

Additional measurement (1 device):  
FWHM (277eV) = 61 eV

readout speed: 165  $\mu$ s/frame;

measurements over a wide energy range from 500 eV to 10 keV

